

MOS FIELD EFFECT TRANSISTOR NP22N055HHE, NP22N055IHE

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

These products are N-channel MOS Field Effect Transistors designed for high current switching applications.

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance $R_{DS(on)1} = 39 \text{ m}\Omega \text{ MAX.} (V_{GS} = 10 \text{ V}, \text{ Id} = 11 \text{ A})$

• Low Ciss : Ciss = 590 pF TYP.

Built-in gate protection diode

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^{\circ}C$)

Drain to Source Voltage	Vdss	55	V
Gate to Source Voltage	Vgss	±20	V
Drain Current (DC)	D(DC)	±22	Α
Drain Current (Pulse) Note1	D(pulse)	±55	А
Total Power Dissipation (T _A = 25°C)	P⊤	1.2	W
Total Power Dissipation (Tc = 25°C)	P⊤	45	W
Single Avalanche Current Note2	las	13 / 5	А
Single Avalanche Energy Note2	Eas	16 / 25	mJ
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C

ORDERING INFORMATION

PART NUMBER	PACKAGE	
NP22N055HHE	TO-251	
NP22N055IHE	TO-252	



(TO-251)

(TO-252)



Notes 1. PW \leq 10 μ s, Duty cycle \leq 1 %

2. Starting $T_{ch} = 25^{\circ}C$, $R_G = 25 \Omega$, $V_{GS} = 20 V \rightarrow 0 V$ (See Figure 4.)

THERMAL RESISTANCE

Channel to Case	Rth(ch-C)	3.33	°C/W
Channel to Ambient	Rth(ch-A)	125	°C/W

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Document No. D14135EJ3V0DS00 (3rd edition) Date Published March 2001 NS CP(K) Printed in Japan

The mark \star shows major revised points.

ELECTRICAL CHARACTERISTICS (TA = 25 °C)

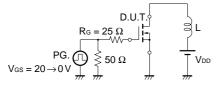
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)	Vgs = 10 V, Id = 11 A		30	39	mΩ
Gate to Source Threshold Voltage	VGS(th)	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2.0	3.0	4.0	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 11 A	4	8		S
Drain Leakage Current	loss	$V_{DS} = 55 V, V_{GS} = 0 V$			10	μA
Gate to Source Leakage Current	lgss	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			±10	μA
Input Capacitance	Ciss	$V_{DS} = 25 V$, $V_{GS} = 0 V$, $f = 1 MHz$		590	890	pF
Output Capacitance	Coss			110	170	pF
Reverse Transfer Capacitance	Crss			52	94	pF
Turn-on Delay Time	td(on)	$I_{D} = 11 A, V_{GS(on)} = 10 V, V_{DD} = 28 V,$		11	24	ns
Rise Time	tr	$R_G = 1 \Omega$		6.0	15	ns
Turn-off Delay Time	$t_{d(off)}$			25	49	ns
Fall Time	tr			6.6	17	ns
Total Gate Charge	Q _G	$I_D = 22 \text{ A}, V_{DD} = 44 \text{ V}, V_{GS} = 10 \text{ V}$		12	18	nC
Gate to Source Charge	Q _{GS}			3		nC
Gate to Drain Charge	Qgd			5		nC
Body Diode Forward Voltage	VF(S-D)	IF = 22 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	$I_F = 22 \text{ A}, \text{ V}_{GS} = 0 \text{ V}, \text{ di/dt} = 100 \text{ A}/\mu \text{s}$		35		ns
Reverse Recovery Charge	Qrr			42		nC

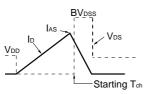
TEST CIRCUIT 1 AVALANCHE CAPABILITY

TEST CIRCUIT 2 SWITCHING TIME

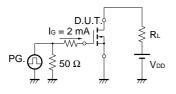
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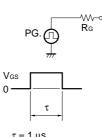
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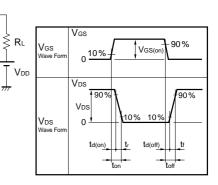


TEST CIRCUIT 3 GATE CHARGE



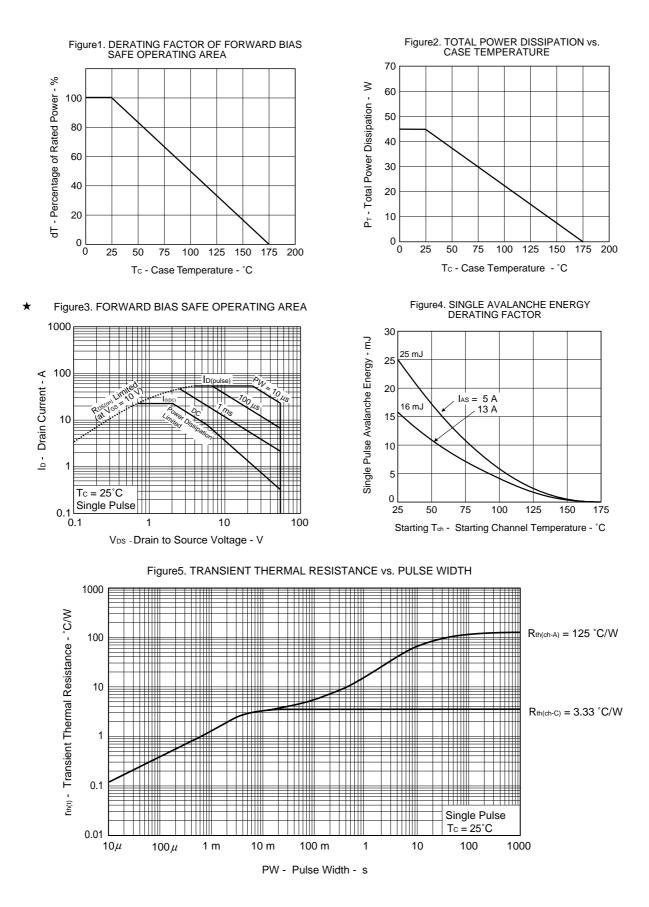






TYPICAL CHARACTERISTICS (TA = 25 °C)

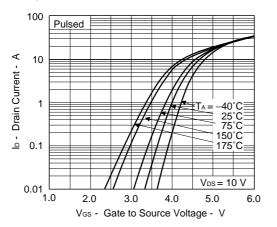
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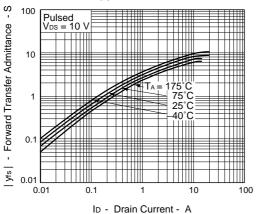
Data Sheet D14135EJ3V0DS

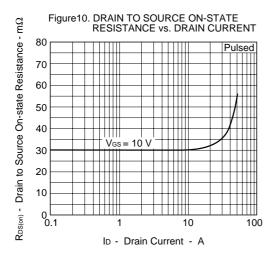
Figure6. FORWARD TRANSFER CHARACTERISTICS

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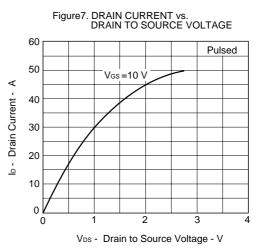
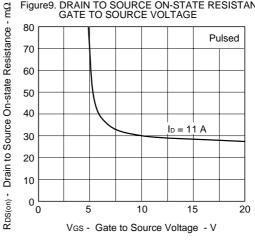
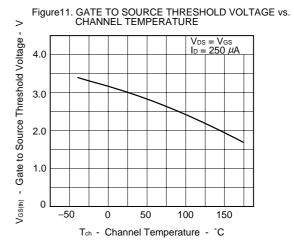
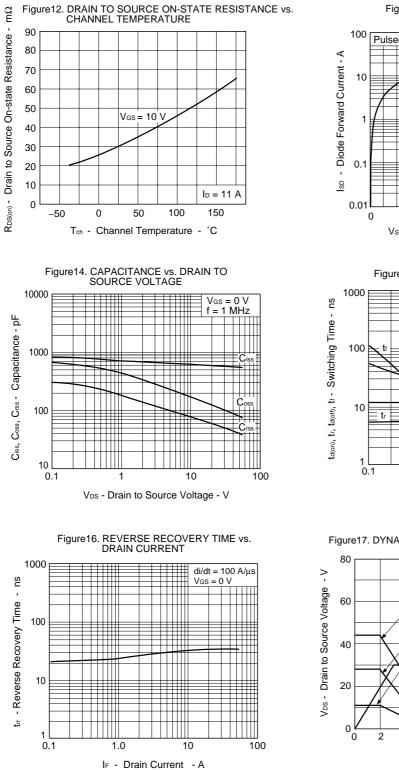


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE







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Figure13. SOURCE TO DRAIN DIODE FORWARD VOLTAGE

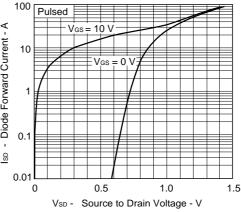


Figure 15. SWITCHING CHARACTERISTICS

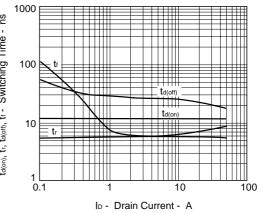
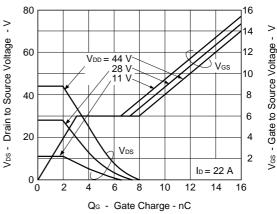
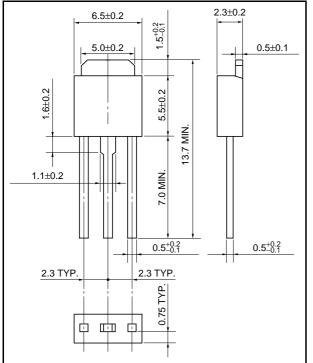


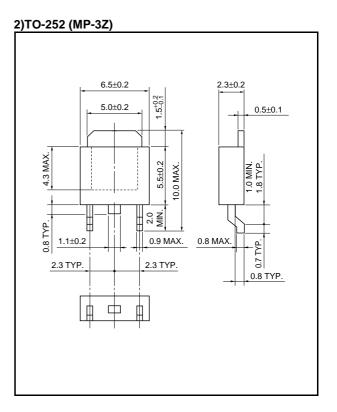
Figure17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS



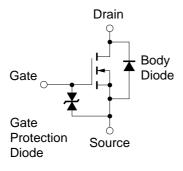
PACKAGE DRAWINGS (Unit: mm)

1)TO-251 (MP-3)





EQUIVALENT CIRCUIT



Remark 1. These products are an electrostatic sensitive device. Please handle with caution.

2. The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

[MEMO]

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